

Sample Submission Form for Example Measurements

In order to provide the best and most appropriate measurement/results, the customer is asked to please fill in the following form and enclose it with the sample. (на английском или русском языке)
This form or equivalent information is required prior to the sample measurements.

Customer Details:

Name:	E-Mail:	Phone:
_____	_____	_____
Institution:	City, Country:	Fax:
_____	_____	_____

Sample Description / Sample Properties:

Transparent Opaque Dimensions: _____ Substrate: _____

General description of the samples (if necessary please also note aspects of storage, toxicity or general handling of the sample). If more than one samples are provided, please prioritize the different samples and identify clearly where on the sample the measurement should be performed:

Requested Measurement Modes:

- Atomic Force Microscopy (AFM) AC Mode Pulsed Force Mode
- Confocal Raman Microscopy
- Scanning Near-field Optical Microscopy (SNOM) Other



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Sample Preparation:

In general, the sample should be fully prepared for microscopic measurements. WITec can not provide specialised sample preparation.

Measurement Goal:

What's the goal of the measurement? If possible please provide existing images or spectra.

Как вы планируете использовать результаты:

- | | |
|-------------------------------------------------------------|----------------------------------------------------------------|
| <input type="checkbox"/> Представить в статье | <input type="checkbox"/> подать заявку на грант |
| <input type="checkbox"/> показать актуальность исследований | <input type="checkbox"/> подать заявку на закупку оборудования |